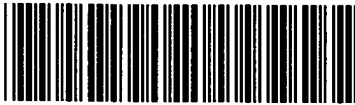


Search Notes

Application/Control No.

10/823,170

Examiner

/Yonel Beaulieu/

Applicant(s)/Patent under
Reexamination

NAIK ET AL.

Art Unit

3661

SEARCHED

Class	Subclass	Date	Examiner
702	108	6/14/2007	YB
	127		
714	735-736		
701	1		
	29		
	34		
	36		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
See attached Int. Search		6/14/2007	YB

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
WEST+Int.+Fwd/Bwd	6/14/2007	YB